

SPECIFICATION CV.4094

ISSUE 1 DATED 8.1.59

AMENDMENT No. 1

Page 2 GROUP C

Immediately following the test for "Mutual Conductance (3)"

Add new test as follows:-

<u>Test</u>	<u>Test</u> <u>Conditions</u>	<u>AQL</u> <u>%</u>	<u>Insp.</u> <u>Level</u>	<u>Sym-</u> <u>bol</u>	<u>Limits</u>		<u>Units</u>
					<u>Min.</u>	<u>Max.</u>	
Mutual Conductance (4)	Vf = 0.8V	2.5	I	gm	1.1	-	mA/V

April, 1959.
N.54788/D.

T.V.C. for S.R.D.E.

ELECTRONIC VALVE SPECIFICATIONS

SPECIFICATION MOS/CV4094

ISSUE NO.1 DATED 8.1.59.

AMENDMENT NO.2

On Page 4, under GROUP F
(Cont'd)
Intermittent
Life Test

(1) Delete Life Test
End Point
(500 hours)

(2) Immediately following the above, in
column headed "Test"

Amend Life Test to read Life Test
End Point End Point
(1,000 hours) (500 hours)

TVC for SRDE

August, 1959

N.71076/D

Specification MOS/CV4094 Issue 1 Dated 8.1.59 To be read in conjunction with K.1001, BS448 and BS1409	<u>SECURITY</u>	
	<u>Specification</u> Unclassified	<u>Valve</u> Unclassified

—————> Indicates a change

Type of Valve - Reliable R.F. Beam Tetrode Sharp Cut Off Cathode - Directly Heated Envelope - Glass Metallised Prototype - VX9186		<u>MARKING</u>	
		See K1001/4 except that the valve shall only be marked with the CV No. factory and date code	
<u>RATING</u> (All limiting values are absolute)		<u>BASE</u>	
		See App. 1 to CV2237 BS 448/B5G/F	
		<u>CONNECTIONS</u>	
		<u>PIN</u>	<u>ELECTRODE</u>
		1	a (red dot)
		2	g ₂
		3	f (-), bp ₁ , M
		4	g ₁
		5	f (+), bp ₂
<u>Typical Operating Conditions</u>		<u>DIMENSIONS</u>	
Measured at $V_a = V_{g2} = 45V, V_{g1} = 0$ $R_{g1} = 2 M\Omega$		See BS448/B5G/F Size Reference No. 1 See App. 1 to CV2237	
Anode Current (mA)	3.0	Dimensions (millimetres)	Min. Max.
Screen Current (mA)	0.9	A. Overall Length	- 38.15
Mutual Conductance (mA/V)	2.0	Diameter	- 7.264
		B. Minor	- 9.804
		C. Major	- 9.804
		Lead Length	38.1
<u>Capacitances (pF)</u>		<u>MOUNTING POSITION</u>	
C_{in} (nom.)	4.0	ANY	
C_{out} (nom.)	4.0		
$C_{a, g1}$ (max.)	0.01		

To be performed in addition to those applicable in K.1001. Tests shall be performed in the specified order unless otherwise agreed with the inspecting Authority.

Test conditions - unless otherwise specified								
V _f (V)	V _a (V)	V _{G2} (V)	V _{G1} (V)	R _{G1} (Megohms)				
1.25	45	45	0	2				
K.1001 Ref.	Test	Test Conditions	AQL %	Insp. Level	Symbol	Limits		Units
						Min.	Max.	
7.1	Glass Strain	No Voltages	6.5	I				
	<u>GROUP A</u>							
	Electrode Insulation	V _f = 0 V _{G1} - all = -100V V _{G2} - all = -100V V _a - all = -100V		100%	R R R	100 100 100		MΩ MΩ MΩ
	Reverse Grid Current	R _{G1} = 500 kΩ max. V _a = V _{G2} = 55V V _{G1} = -1.0V		100%	I _{G1}	-	0.5	μA
	Contact Potential	V _f = 1.25V V _a = V _{G2} = 0 R _{G1} = 200 kΩ		100%	I _{G1}	0.25		μA
	<u>GROUP B</u>	Combined AQL	1.0	II				
	Filament Current		0.65	II	I _f	88	122	mA
	Anode Current		0.65	II	I _a	1.9	4.1	mA
	Screen Grid Current		0.65	II	I _{G2}	0.5	1.3	mA
	Mutual Conductance (1)		0.65	II	g _m	1.5	2.5	mA/V
	<u>GROUP C</u>	Combined AQL	6.5	I				
	Mutual Conductance (2)	V _f = 1.0V	2.5	I	g _m	1.2	2.5	mA/V
	Mutual Conductance (3)	V _f = 1.0V Take reading after 15 mins.	2.5	I	g _m	1.2	2.5	mA/V
	Anode Resistance		2.5	I	R _a	0.2		MΩ
	R.F. Noise	E _{sig} = 30 mVrms Ref. K.1006 (4.10.3.1)	2.5	I				

K.1001 Ref.	Test	Test conditions	AQL %	Insp. Level	Sym- bol	Limits		Units		
						Min.	Max.			
5.12	<u>GROUP D</u> Lead Fragility	Note 1 Measured on a 1Mc/s bridge with the valve mounted in a fully screened socket. No shield.	6.5	IA	Ca, C ₁ C _{in} C _{out}	3	5	pF		
	Filament Anode Short			T.A.						
	Capacitances		6.5	IC					0.01	pF
	Functional Test			T.A.					The valves shall operate satisfac- torily in W.S. A40 and A41	
11.3	<u>GROUP E</u> Fatigue	Acceleration = 5g peak min. Time = 99 hours Note 2		IA						
	<u>Post Fatigue Tests</u>	Combined AQL	4.0							
	R.F. Noise	As in Group C	2.5							
	Mutual Conductance (1)		2.5		gm	1.2		mA/V		
	11.4	Shock	No voltages. Hammer Angle 30°		IA					
		<u>Post Shock Tests</u>	Combined AQL	4.0						
R.F. Noise		As in Group C	2.5							
	Mutual Conductance (1)		2.5		gm	1.2		mA/V		
A VI/5 A VI/ 5.1	<u>GROUP F</u> Life	Rg ₁ = 5 MΩ								
	<u>Stability Life Test</u>									
	Mutual Conductance (2)	Vf = 1.0V	1.0	I	gm	1.2		mA/V		

K.1001 Ref.	Test	Test Conditions	AQL %	Insp. Level	Sym- bol	Limits		Units
						Min.	Max.	
A VI/ 5.3	<u>GROUP F</u> (Cont'd)							
	<u>Intermittent Life Test</u>							
	<u>Life Test End Point (500 hrs.)</u>	Combined AQL	6.5	IA				
A VI/ 5.6	Inoperatives		2.5					
	Mutual Conductance (1)		2.5		gm	1.2		mA/V
	Electrode Insulation	Vf = 0 Vg ₁ - all = -100V Vg ₂ - all = -100V Va - all = -100V	4.0		R R R	50 50 50		MΩ MΩ MΩ
	<u>Life Test End Point (1,000hrs.)</u>	Combined AQL	10	IA				
A VI/ 5.6	Inoperatives		4.0					
	Mutual Conductance (1)		4.0		gm	1.2		mA/V
	Reverse Grid Current	As in Group A	4.0		Ig ₁	-	1.0	μA
	Contact Potential	Vf = 1.25V Va = Vg ₂ = 0 Rg ₁ = 200kΩ	4.0		Ig ₁	To be recorded		
	Electrode Insulation	Vf = 0 Vg ₁ - all = -100V Vg ₂ - all = -100V Va - all = -100V	6.5		R R R	30 30 30		MΩ MΩ MΩ
A IX/ 2.4 and 2.5	<u>GROUP G</u> Electrical retest after 28 days hold- ing period			100%				
A VI/ 5.6	Inoperatives		0.5					
	Mutual Conductance (1)				gm	1.5	2.5	mA/V
	Reverse Grid Current	As in Group A	0.5		Ig ₁	-	0.5	μA

NOTES

1. Raise V_f until filament opens. Test for filament to anode short only. After performance of the filament burn out test, if the short circuit shall pass in excess of five times the rated filament current without burning out the short circuit, the valve shall be deemed a failure. This test shall be performed by a Service Laboratory on three valves which shall be in addition to the required number for Type Approval samples. Manufacturers' data are not required for this test.
2. Filament voltage and H.T. voltage switched simultaneously 1 min. on and 3 min. off throughout duration of test. Frequency = 170 cps. The valves to be vibrated in each of three mutually perpendicular planes in turn for periods of 30, 30 and 39 hours. One plane to include the longitudinal axis of the valve.